

# METROLOGIA-2000

São Paulo, SP, Brazil 4-7 December 2000

An international event organized by the Brazilian Society of Metrology



To further its mission of promoting the development of Brazilian Metrology, encouraging the adoption of modern practices and international tendencies, bringing people and institutions together and instigating the interchange of national and international specialists and experiences, the **Brazilian Society of Metrology** (SBM) has great satisfaction in announcing **METROLOGIA-2000**, an international version of the **II Brazilian Congress of Metrology**, to be held in the city of

São Paulo (Brazil) from 4 to 7 December 2000.

**METROLOGIA-2000** is being organized in the context of important celebrations related to the 500<sup>th</sup> anniversary of the discovery of Brazil. It also marks 100 years of the Quanta Max Plank Theory, announced in 1900, allowing - one century later - the genesis of today's technology, based on the fundamental constants of physics. This is the theme under which **METROLOGIA-2000** will take place, "promoting metrology in the light of great discoveries".

**METROLOGIA-2000** is a strategic event, and will be attended by professionals from the Brazilian business community, together with academics, renowned specialists, researchers and metrologists from other countries linked to important international metrological organizations.

Despite the specialist nature of the Associated Events (see below), the Congress is an international event that is open to all those interested in metrology.

## 1. Structure

- (i) **General Congress;**
- (ii) **Exhibitors** (Laboratories, Manufacturers and Distributors of Measuring Instruments);
- (iii) **Technical Sessions** with the presentation of original work in metrology focusing techniques, methods and procedures for calibration and testing related to measurements and the expression of associated uncertainties;
- (iv) **Seminar and Discussion Session** given by internationally respected specialists;
- (v) **Education and Training Module**, made up of specialist metrology courses for selected small groups, reflecting previously identified demands; and
- (vi) **Associated Events** (see opposite).

## 2. Themes

- ▶ Scientific and industrial metrology;
- ▶ Legal metrology;
- ▶ Instrumentation, automation and infrastructure for metrology;
- ▶ Metrology, laboratory quality and confidence;
- ▶ Accreditation of laboratories;
- ▶ International recognition of the accreditation scheme;
- ▶ Social and economic relevance of metrology;
- ▶ Advances and applications in different specialties of metrology, including chemical, electrical, optical, mechanical, thermal, acoustic and vibrations, ionizing radiation, time and frequency, rheological characterization of fluids; and
- ▶ Research, development and education in metrology.

## 3. Associated Events

- ▶ **METROCHEM** (II Inter-American Congress on Metrology in Chemistry)  
Coordinator: Vera Ponçano (IPT), poncano@ipt.com.br
- ▶ **SEMETRO** (IV International Seminar on Electrical Metrology)  
Coordinator: Luiz Carlos Santos (DIMCI/INMETRO), lcgomes@inmetro.gov.br
- ▶ **SEMEL** (International Seminar on Legal Metrology)  
Coordinators: Júlio César Felix (IPEM/PR, Paraná Metrology), jfelix@tepar.br and Roberto L. Guimarães (INMETRO), rlguimaraes@inmetro.gov.br
- ▶ **METRO-TELECOM** (II Seminar on Metrology in Telecommunication)  
Coordinator: Celso Pinto Saraiva (CPqD), celso@cpqd.com.br
- ▶ **METROPT** (Advances in the Application of Optical Metrology)  
Coordinator: Carlos Alberto Massone (INMETRO), diopt@inmetro.gov.br
- ▶ **ENLAB** (II National Encounter of Accredited Laboratories)  
Coordinators: Galdino Guttman Bicho (INMETRO), ggbicho@inmetro.gov.br and Helio Lionel (CENPES/Petrobras), lionel@openlink.com.br

*Note:* ENLAB-2000 is open to all laboratories, accredited or not, interested in advances in metrology, notably in the economic benefits associated with accreditation and the implications due to the transformation of the ISO/IEC Guide 25 into the new Standard ISO/IEC 17025.

#### 4. Call for technical papers / scientific contributions

With the aim of giving an outlet for technical-scientific production in metrology and to create a specialized forum to debate and divulge this important intellectual production, the **Brazilian Society of Metrology** invites specialists and professionals involved in research and the rendering or utilization of metrological services, to submit original articles with proven contribution for presentation in the Technical Sessions. The paper should be in the form of a Summary, in A4 format, maximum of one page, describing the contribution, the authors, positions and complete institutional and e-mail addresses for contact.

After analysis of the Summaries, the authors will receive editorial instructions and invitations to submit the full paper, permitting the Editorial Board to approve its inclusion in the *Proceedings of METROLOGIA-2000*, as well as its eventual recommendation for submission for publication in the *Revista Brasileira de Metrologia* (RBM). This is the SBM's commitment in demonstrating national competence in metrology and promoting an intense interaction and effective networking around the diverse themes related to science, technology and the art of measurement. The process of the inclusion of papers in the Technical Sessions will be:

- Submission deadline for Summaries: ..... 17 July 2000
- Notification of Summary acceptance: ..... 31 July 2000
- Deadline for full Paper submission: ..... 18 Oct. 2000
- Notification of Paper acceptance: ..... 1 Nov. 2000

#### 5. Organizational Commission of METROLOGIA-2000

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| ▶ Armando Mariante (INMETRO President)                                 | ▶ José Joaquim Vinge (INMETRO)                |
| ▶ José Manuel de Aguiar Martins (SENAI-DN President)                   | ▶ Júlio César Felix (IPEM/PR)                 |
| ▶ Maurício Nogueira Frota (President, SBM and <b>METROLOGIA-2000</b> ) | ▶ Luiz Carlos Santos (INMETRO)                |
| ▶ Alfredo G. R. Oliveira (Hidroquímica)                                | ▶ Mário Bonatti Maurício (Panambra)           |
| ▶ Carlos Alberto Massone (INMETRO)                                     | ▶ Mauro Miaguti (FIESP)                       |
| ▶ Celso Pinto Saraiva (CPQD)   | ▶ Ozires Silva (SBM/Council, VARIG President) |
| ▶ Galdino Guttman Bicho (INMETRO)                                      | ▶ Pedro Buzatto Costa (Abimaq)                |
| ▶ Hélio Lionel (CENPES/Petrobras)                                      | ▶ Reinaldo Ferraz Dias de Souza (MCT)         |
| ▶ Jorge Milton Elian Saffar (CETEC)                                    | ▶ Roberto L. Lima Guimarães (INMETRO)         |
|  | ▶ Vera Ponçano (IPT)                          |
|  | ▶ Wilson Radi El Maftoum (LACTEC)             |

In addition to the organizational and operational tasks, this Committee will benefit from the support and experience of members of the SBM that form the technical-scientific community to evaluate the papers submitted to the Technical Sessions.

#### 6. International Scientific Advisory Committee

With the purpose of assuring the quality and relevance of **METROLOGIA-2000**, i.e. to reflect current themes and advances in metrology and its impact on health, the environment, the quality of life and the development of competitiveness, the Organizational Commission will benefit from the advice and orientation of an **International Scientific Advisory Committee** of a high level which brings together specialists from Brazil and from the principal international Metrology Organizations, formed by:

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| ▶ Birch, John (Asia-Pacific Legal Metrology Forum, Australia)  | ▶ Gilmour, John (ILAC, NATA, Australia)                              | ▶ Plantenga, T. Menno (NMI, The Netherlands)               |
| ▶ Birkeland, Knut (OIML, Spain)                                | ▶ Kirschstein, Sven Christian (CODELECTRA, Venezuela)                | ▶ Popa, Marcel (Technical University Cluj-Napoca, Romania) |
| ▶ Bode, Peter (Technical University of Delft, The Netherlands) | ▶ Kochsiek, Manfred (OIML, PTB, Germany)                             | ▶ Schneider, C.A. (Certi, Brazil)                          |
| ▶ Bonnier, Georges (BNM, France)                               | ▶ Laiz, Hector (INTI, Argentina)                                     | ▶ Seiler, Eberhard (IMEKO, PTB, Germany)                   |
| ▶ Carneiro, Kim (DFM, Denmark)                                 | ▶ Lira Canguilhem, Ignacio (Asociación Chilena de Metrología, Chile) | ▶ Semerjian, Hratch G. (NIST, USA)                         |
| ▶ Carpenter, Stephen (NIST, USA)                               | ▶ Moscati, Giorgio (CIPM, Brazil)                                    | ▶ Valdes, Joaquim (CIPM, Univ. San Martin, Argentina)      |
| ▶ Chambon, Maguelonne (BNM, France, Euromet)                   | ▶ Nava Jaimes, Hector (CENAM, Mexico)                                | ▶ Wallard, Andrew (CIPM, NPL, UK)                          |
| ▶ Decker, Jennifer (NRC, Canada)                               | ▶ Pfeifer, Tilo (IMEKO, Univ. Aachen, Germany)                       |  |
| ▶ Delgado, Cecília (Asociación Mexicana de Metrología)         |  |  |

#### 7. Further information

General information can be obtained from the Executive Office of the **Brazilian Society of Metrology**



**Guilherme HUGUET**  
Executive Secretary, SBM

Tel: (55) 21 544-5751, ext. 211  
Fax: (55) 21 544-5527  
E-mail: sbm@redetec.org.br

**Maurício Nogueira FROTA**  
President, SBM and **METROLOGIA-2000**  
E-mail: mfrota@mec.puc-rio.br

or directly from the respective Coordinators of the **Associated Events** for technical information. Current information is permanently available at the **Brazilian Society of Metrology** web site: [www.sbm metrologia.org.br](http://www.sbm metrologia.org.br)